



Cold Silicon detectors as Technological Alternative

Vittorio Palmieri and Tapio Niinikoski
CERN EP Division 1211 Geneva 23

on behalf of the
CERN-RD39 Collaboration
<http://www.cern.ch/RD39>



The CERN-RD39 Collaboration

W. H. Bell¹, P. Berglund², W. de Boer³, E. Borchini⁴, K. Borer⁵, M. Bruzzi⁴, S. Buontempo⁶,
L. Casagrande⁷, S. Chapuy⁸, V. Cindro⁹, N. D'Ambrosio⁶, C. Da Viá¹⁰, S. Devine¹,
B. Dezillie¹¹, Z. Dimcovski⁸, V. Eremin¹², A. Esposito¹³, V. Granata^{9,14}, E. Grigoriev^{3,8},
F. Hauler³, E. Heijne¹⁴, S. Heising³, S. Janos⁵, L. Jungermann³, I. Konorov¹³, Z. Li¹¹,
C. Lourenço¹⁴, M. Mikuz⁹, T. O. Niinikoski^{14*}, V. O'Shea¹, S. Pagano⁶, V. G. Palmieri^{14*},
S. Paul¹³, S. Pirollo⁴, K. Pretzl⁵, G. Ruggiero⁶, K. Smith¹, P. Sonderegger¹⁴, M. Valtonen²,
E. Verbitskaya¹², S. Watts¹⁰, M. Zavrtanik⁹
(The CERN-RD39 Collaboration)

¹ University of Glasgow, UK

² Helsinki University of Technology, Espoo, Finland

³ IEKP, University of Karlsruhe, Germany

⁴ INFN and University of Florence, Italy

⁵ LHEP, University of Bern, Switzerland

⁶ INFN and University of Naples, Italy

⁷ LIP, Lisbon, Portugal

⁸ Department of Radiology, University of Geneva, Switzerland

⁹ JSI and University of Ljubljana, Slovenia

¹⁰ University of Brunel, UK

¹¹ Brookhaven National Laboratory, USA

¹² Ioffe PTI, St. Petersburg, Russia

¹³ Technical University of Munich, Germany

¹⁴ CERN, Geneva, Switzerland

*co-spokesperson

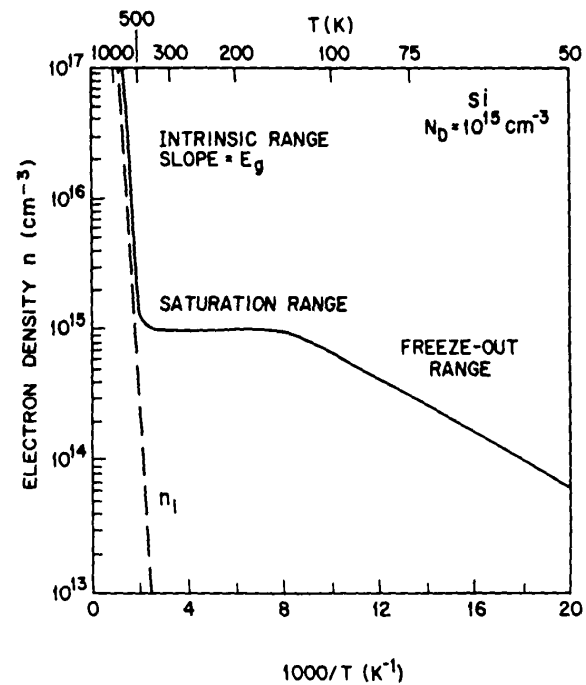
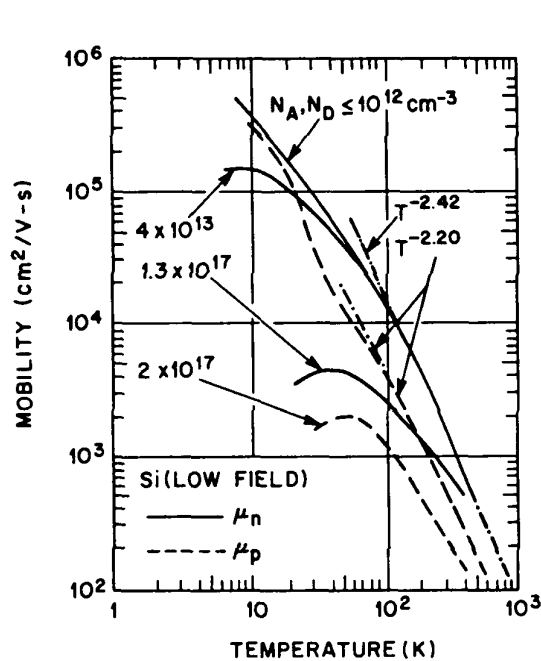


Outline

- ◆ **Properties of Si at cryogenic temperatures**
- ◆ **CCE of heavily irradiated Si detectors at cryogenic temperatures (up to $2 \cdot 10^{15}$ n/cm²)**
- ◆ **Neutralization of induced defects: the Lazarus effect**
- ◆ **Tracking efficiency and position resolution of an irradiated DELPHI module ($4 \cdot 10^{14}$ n/cm²)**
- ◆ **Beam monitoring and diagnostic**
- ◆ **Cold silicon for luminosity measurements**



Properties of Silicon at Cryogenic Temperatures





Why is the present
technology not sufficient ?

... and how can we improve
it ?



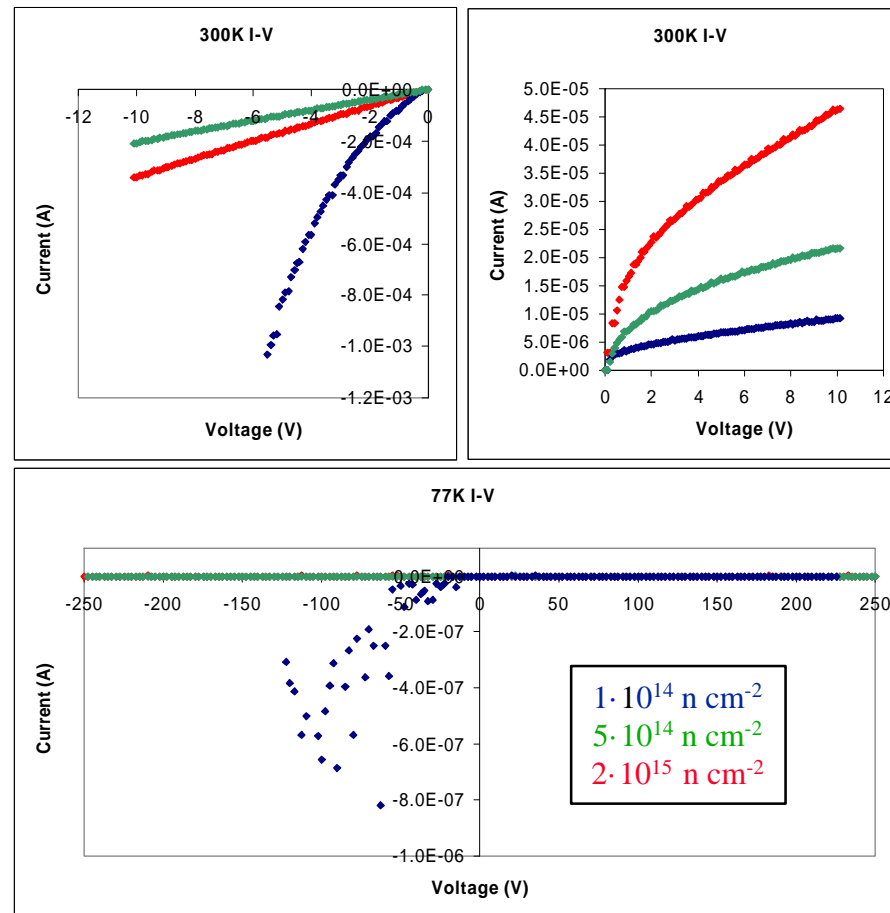
Irradiated Si Detectors

- ◆ Irradiated at room temperature at TRIGA neutron reactor, JSI Slovenia
- ◆ Stored at room temperature and subjected to thermal cycles, therefore strongly reverse annealed (RA)
- ◆ Different materials and processes:
 - Al/n+/n/p+/Al 1.8 k Ω cm
 - Al/n+/n/p+/Al 2.7 k Ω cm
 - Al/n+/n/p+/Al 4 k Ω cm



Current-Voltage Characteristics

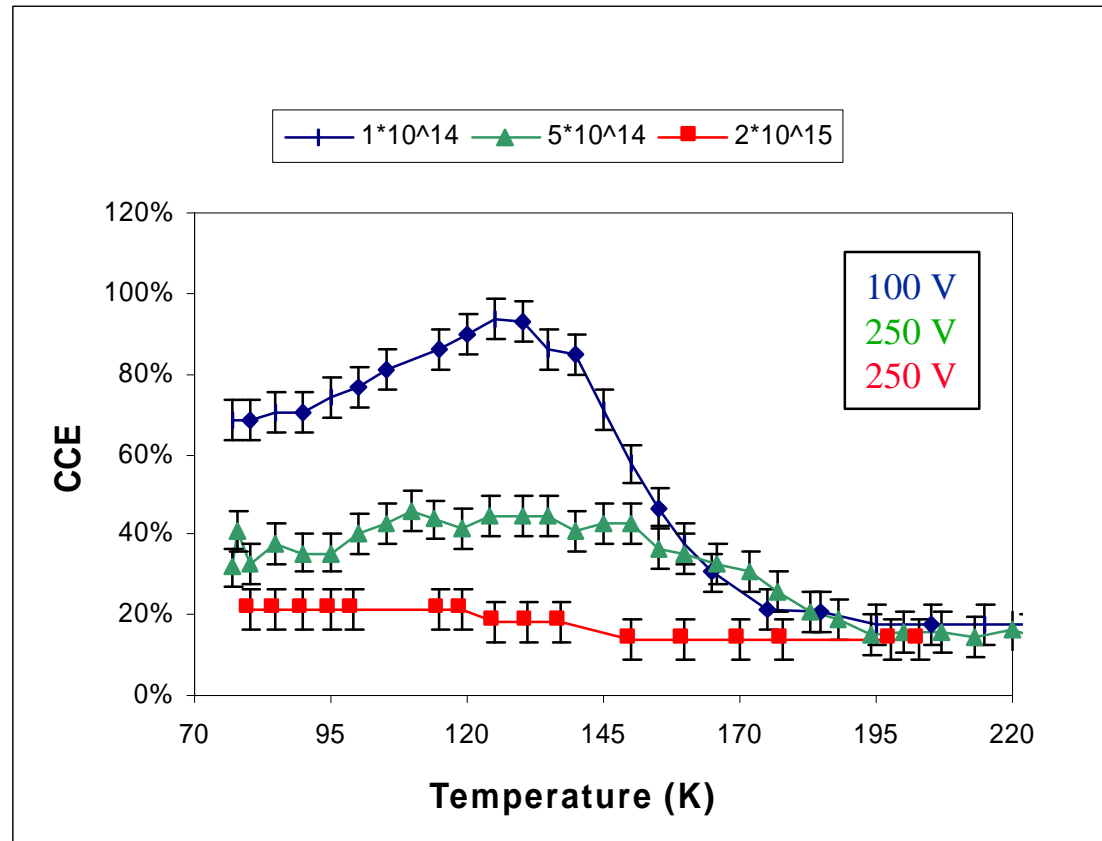
Preliminary





Temperature Dependence of CCE

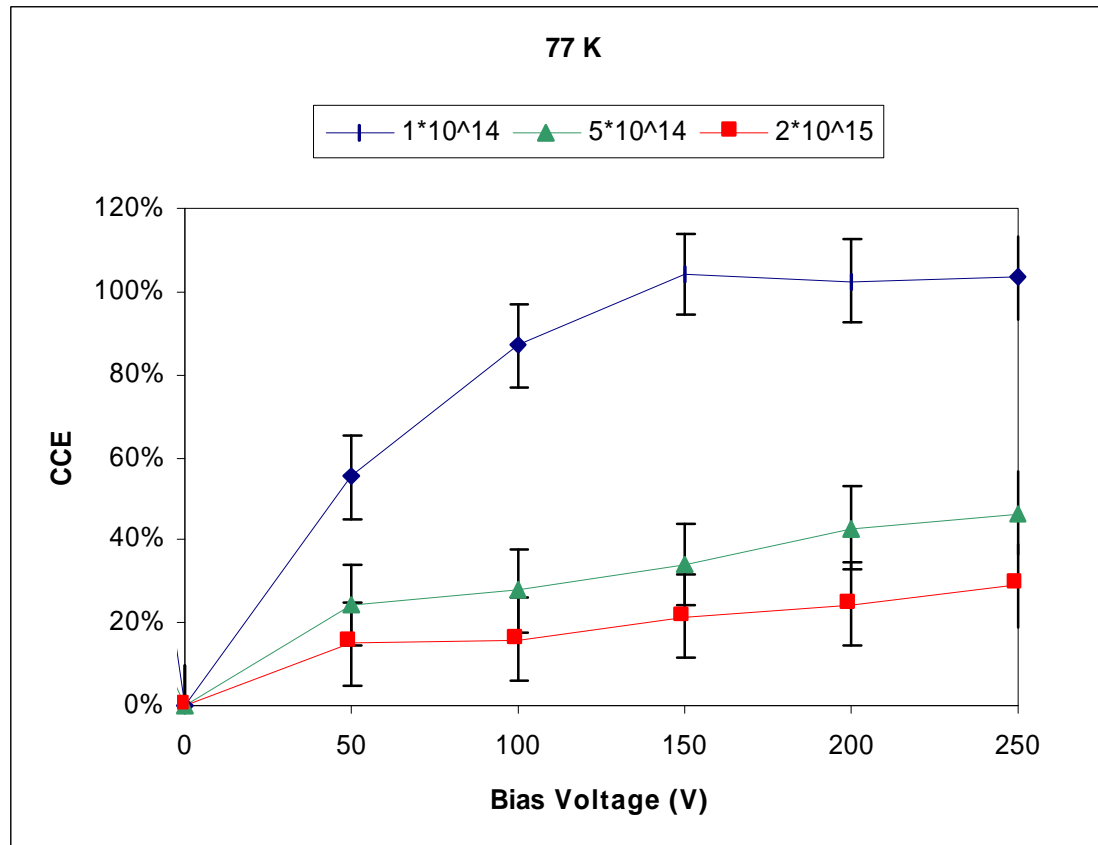
Preliminary





Voltage Dependence of CCE

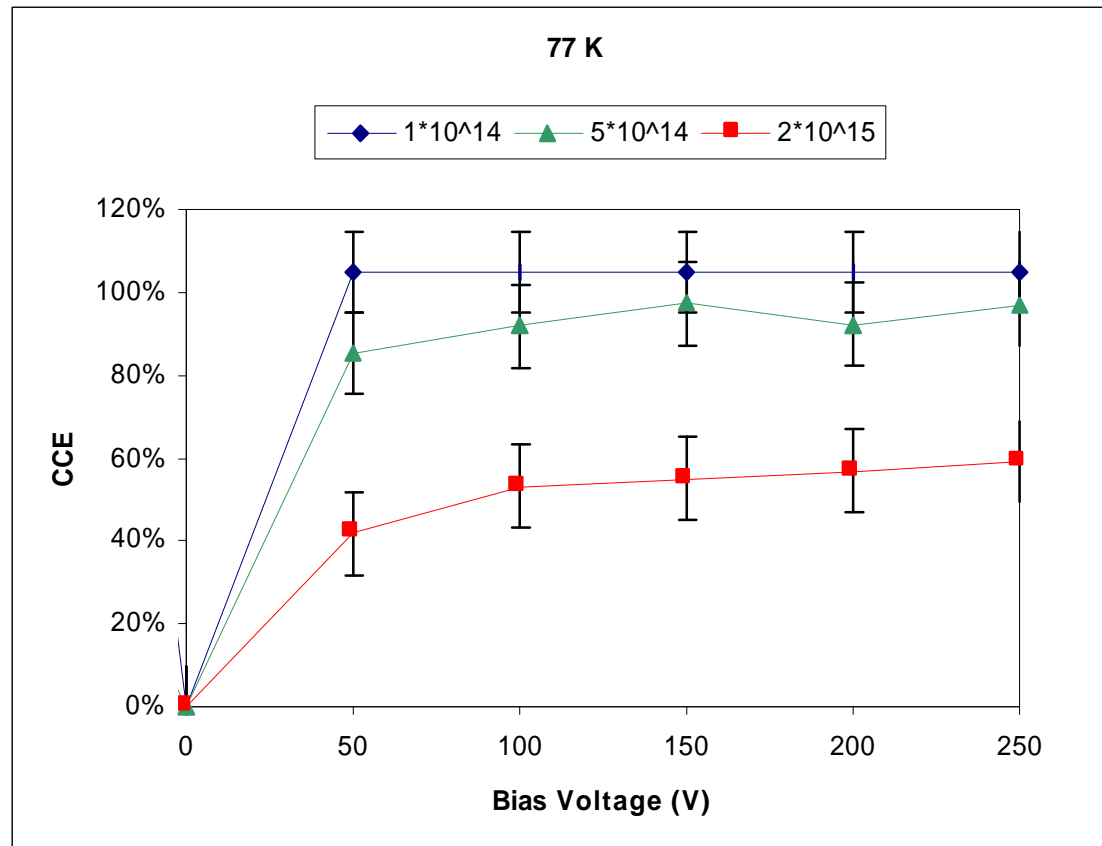
Preliminary





Voltage Dependence of CCE “pumped”

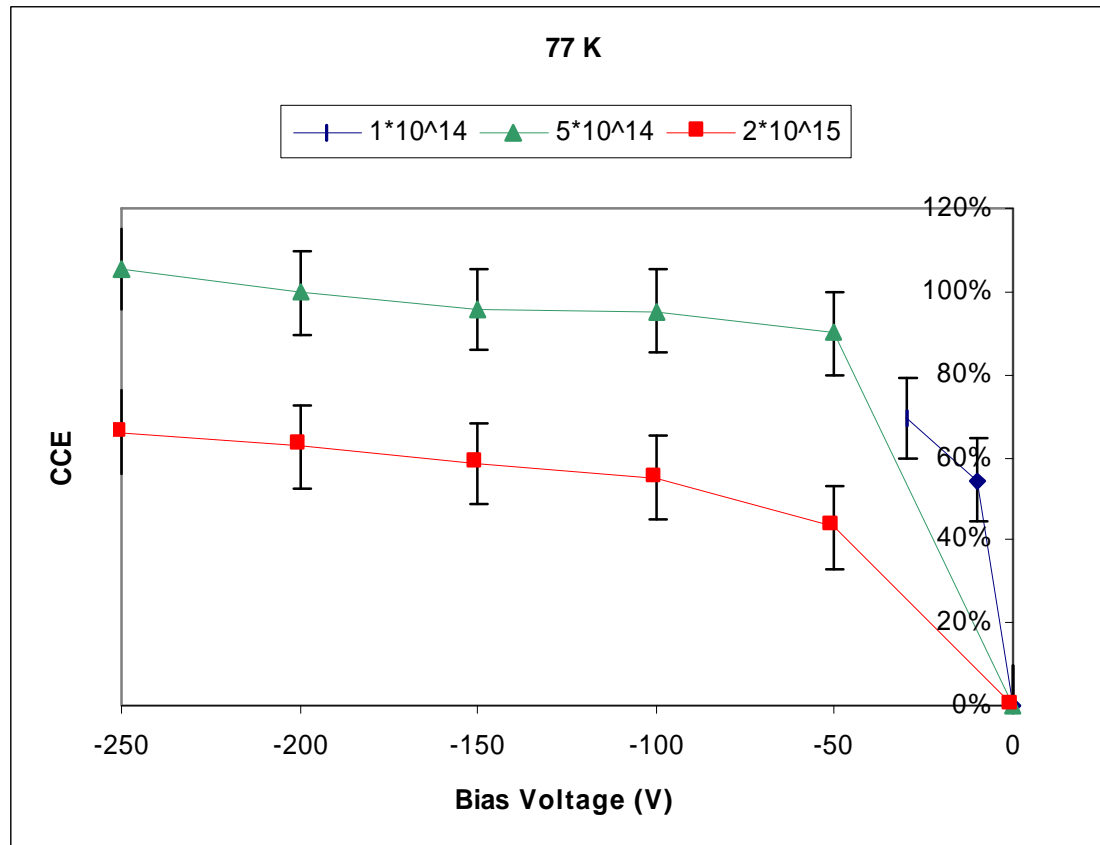
Preliminary





Voltage Dependence of CCE “forward bias”

Preliminary





How do we explain all this ?



The Lazarus Effect



Vittorio Palmieri

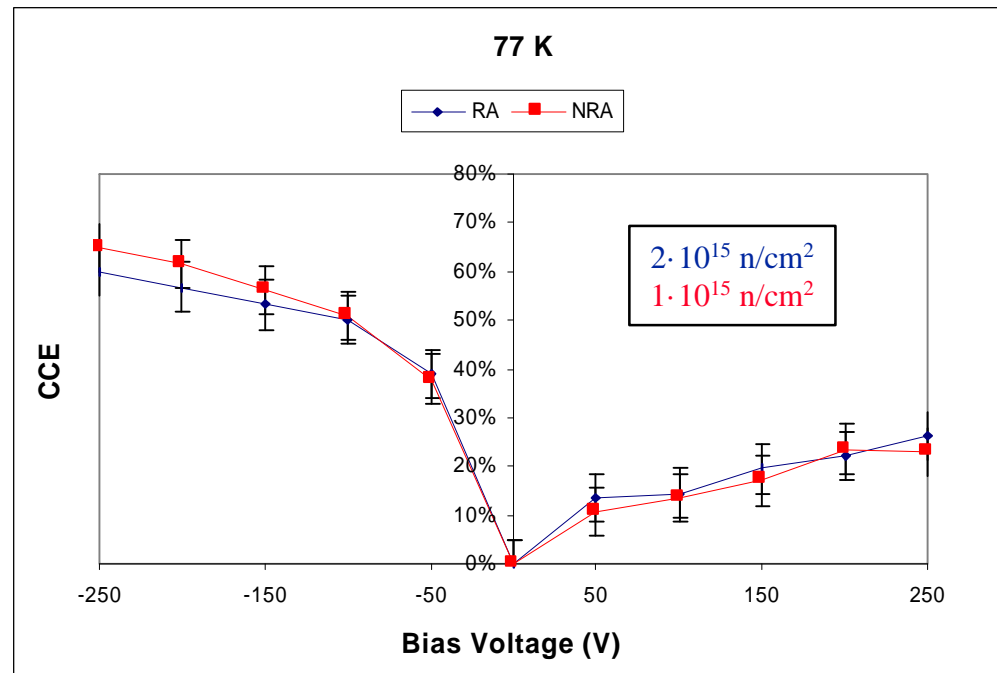


What is the role of long
term annealing?



Annealing Effects ...

Preliminary

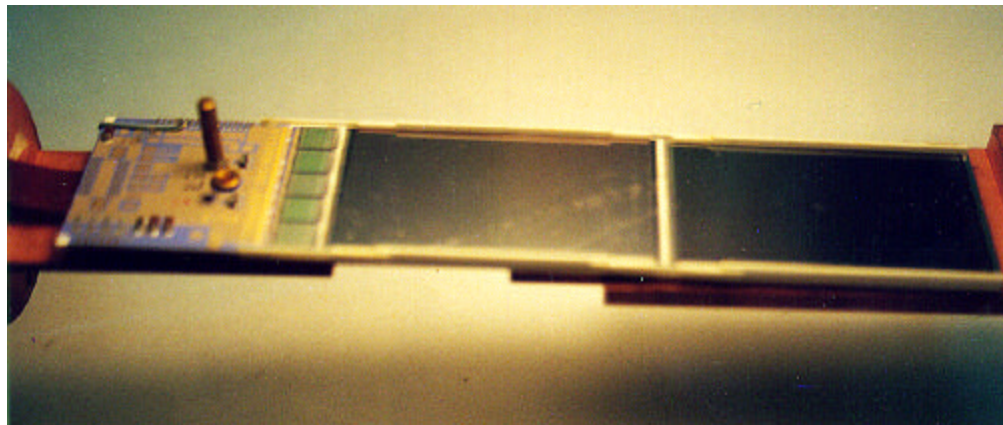




The charge is back, but what about position resolution ?

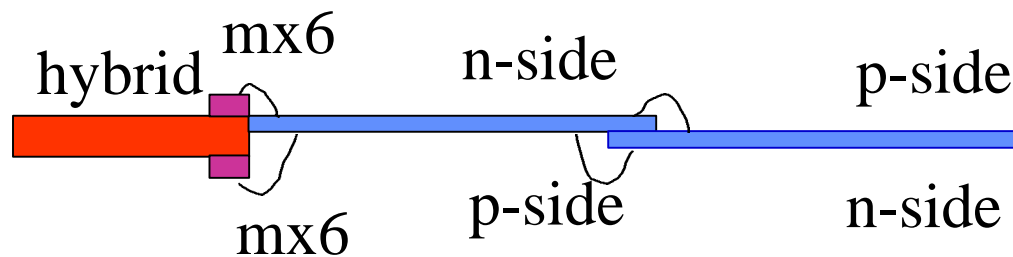


The DELPHI Module



Detectors:

2x Hamamatsu
320 μm 5.75 x 3.2 cm^2 3-6 Kohm cm
p-side 640 strips
strip pitch 25 μm
r-o pitch 50 μm
n-side 640 strips (p-stops)
strip pitch 42 μm
r-o pitch 42 μm



Electronics:

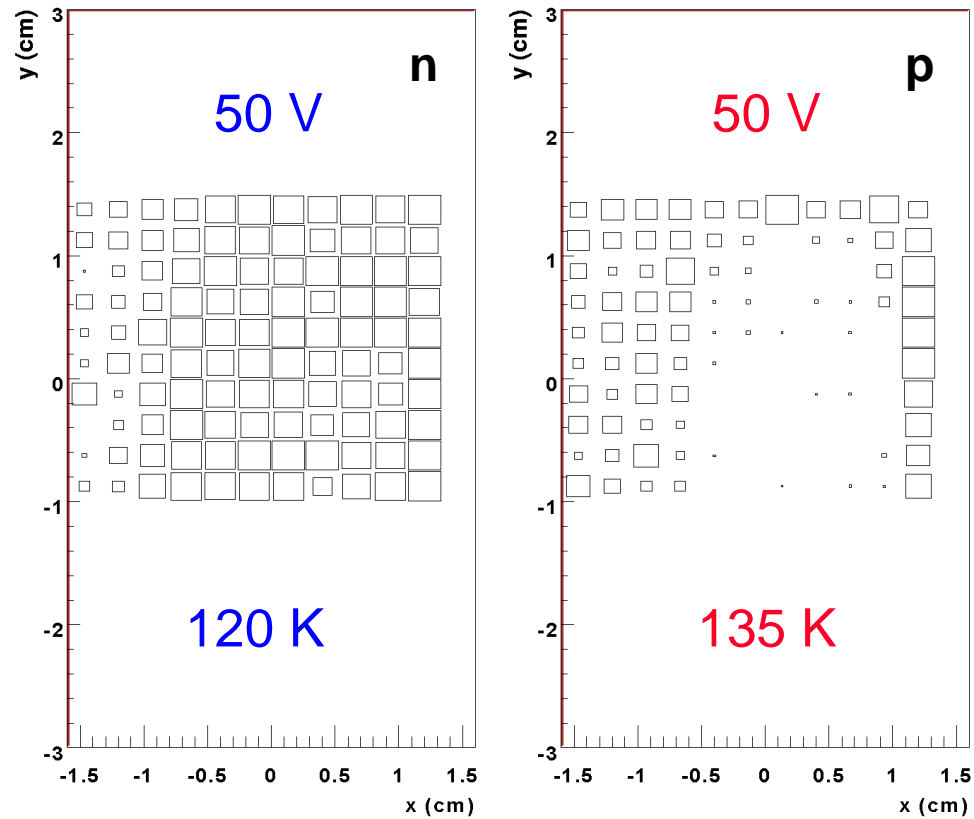
10x Mx6
128 input channels
CMOS technology
2.5 MHz speed
1.5 μs peaking time
“radiation soft”

V. Chabaud et al., CERN-PPE/95-86, 1995



Back from the Dead ...

Preliminary

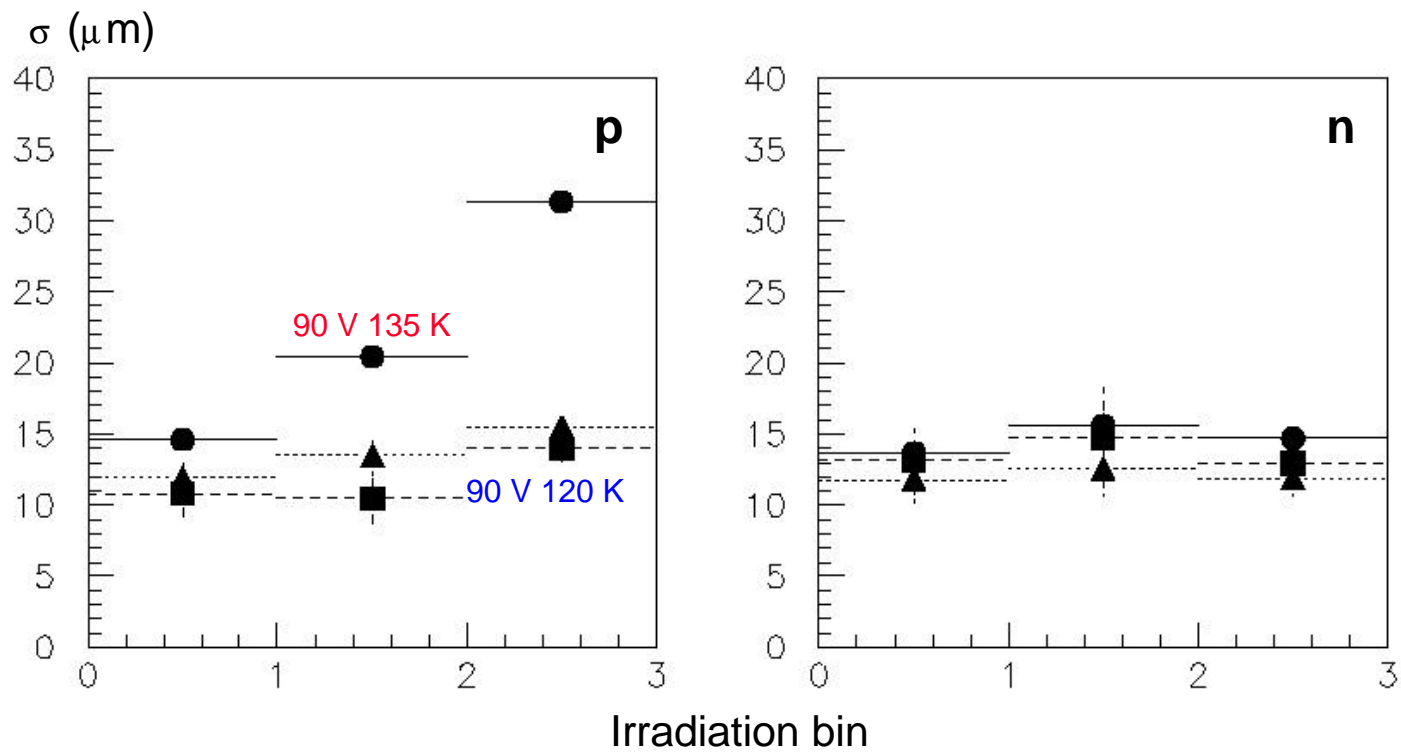


L. Casagrande et al., CERN-EP/98-207, 1995



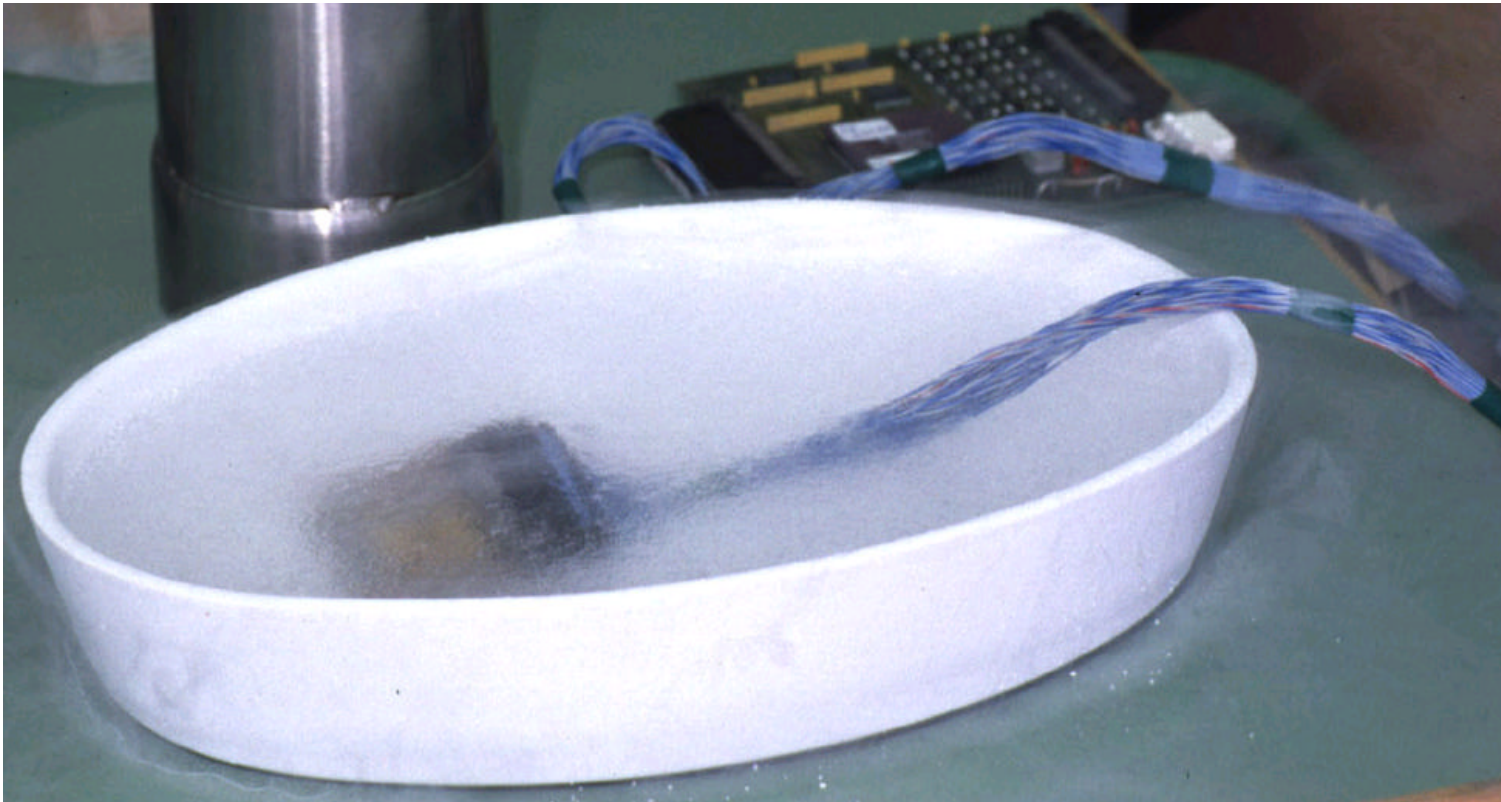
Position Resolution

Preliminary





Cold Pixel Lasagna ...



The Ω -LHC1 pixel chip (courtesy of CERN-RD19)